

# TOSHIBA MOS MEMORY PRODUCT

1M BIT (128K WORD × 8 BIT)  
CMOS MASK ROM  
SILICON GATE CMOS

TC531000AP  
TC531000AF

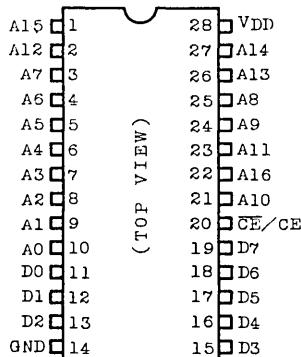
## DESCRIPTION

The TC531000AP/AF is a 1,048,576 bits read only memory organized as 131,072 words by 8 bits with a low bit cost, thus being suitable for use in program memory of microprocessor, especially character generator. The TC531000AP/AF using CMOS technology is most suitable for low power applications where battery operation are required. The TC531000AP/AF has one chip enable input  $\overline{CE}/CE$ , programmable for device selection.

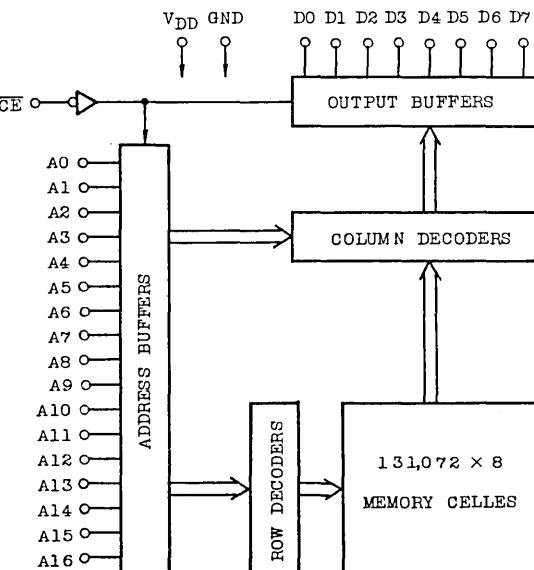
## FEATURES

- Single 5V Power Supply
- Access Time: 150ns (Max.)
- Power Dissipation
- Operating Current: 40mA (Max.)
- Standby Current : 20 $\mu$ A (Max.)
- All Inputs and Outputs: TTL Compatible
- Three State Outputs
- Fully Static Operation
- Programmable Chip Enable
- Package Plastic DIP: TC531000AP  
Plastic FP : TC531000AF

## PIN CONNECTION



## BLOCK DIAGRAM



## PIN NAMES

A0 ~ A16	Address Inputs
D0 ~ D7	Data Outputs
$\overline{CE}/CE$	Chip Enable Input
VDD	Power Supply
GND	Ground

# TC531000AP

# TC531000AF

## MAXIMUM RATINGS

SYMBOL	ITEM	RATING	UNIT
V <sub>D</sub> D	Power Supply Voltage	-0.5 ~ 7.0	V
V <sub>I</sub> N	Input Voltage	-0.5 ~ V <sub>D</sub> D	V
V <sub>O</sub> UT	Output Voltage	0 ~ V <sub>D</sub> D	V
P <sub>D</sub>	Power Dissipation	1.0/0.6*	W
T <sub>S</sub> TG	Storage Temperature	-55 ~ 150	°C
T <sub>O</sub> PR	Operating Temperature	-40 ~ 70	°C
T <sub>S</sub> OLDER	Soldering Temperature • Time	260 • 10	°C•sec

Note: \* Plastic FP

## D.C. OPERATING CONDITIONS (Ta=-40 ~ 70°C)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
V <sub>D</sub> D	Power Supply Voltage	4.5	5.0	5.5	V
V <sub>I</sub> H	Input High Voltage	2.2	-	V <sub>D</sub> D+0.3	V
V <sub>I</sub> L	Input Low Voltage	-0.3	-	0.8	V

## D.C. and OPERATING CHARACTERISTICS (Ta=-40 ~ 70°C, V<sub>D</sub>D=5V±10%)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
I <sub>I</sub> L	Input Leakage Current	V <sub>I</sub> N=0 ~ V <sub>D</sub> D	-	±1.0	µA
I <sub>O</sub> L	Output Leakage Current	CE=V <sub>I</sub> H, V <sub>O</sub> UT=0 ~ V <sub>D</sub> D	-	±5.0	µA
I <sub>O</sub> H	Output High Current	V <sub>O</sub> H=2.4V	-1.0	-	mA
I <sub>O</sub> L	Output Low Current	V <sub>O</sub> L=0.4V	2.0	-	mA
I <sub>D</sub> DS1	Standby Current	CE=V <sub>I</sub> H	-	2	mA
I <sub>D</sub> DS2	Standby Current	CE=V <sub>D</sub> D and V <sub>I</sub> N=0V (V <sub>D</sub> D)	-	20	µA
I <sub>D</sub> D01	Operating Current	V <sub>I</sub> N=V <sub>I</sub> H/V <sub>I</sub> L, t <sub>cycle</sub> =150ns	-	50	mA
I <sub>D</sub> D02		V <sub>I</sub> N=V <sub>D</sub> D/0V, t <sub>cycle</sub> =150ns	-	40	

## CAPACITANCE

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
C <sub>I</sub> N	Input Capacitance	f=1MHz, Ta=25°C	-	10	pF
C <sub>O</sub> UT	Output Capacitance	f=1MHz, Ta=25°C	-	10	

Note: This parameter is periodically sampled and is not 100% tested.

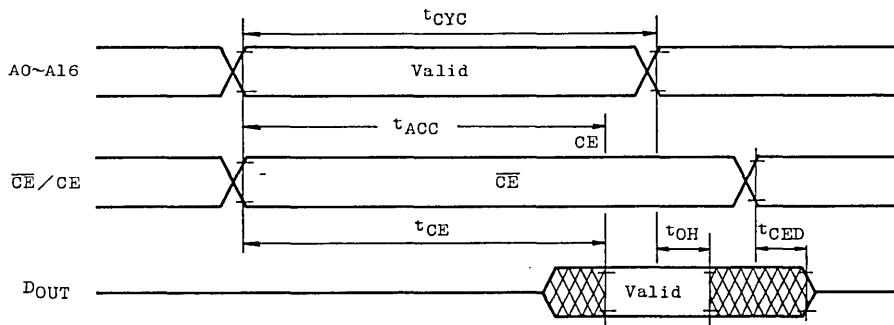
**A.C. CHARACTERISTICS (V<sub>DD</sub>=5V±10%, Ta=-40 ~ 70°C)**

SYMBOL	PARAMETER	MIN.	MAX.	UNIT
t <sub>CYC</sub>	Cycle Time	150	-	ns
t <sub>ACC</sub>	Access Time	-	150	ns
t <sub>CE</sub>	Chip Enable Access Time	-	150	ns
t <sub>CED</sub>	Output Disable Time	-	50	ns
t <sub>OH</sub>	Output Hold Time	0	-	ns

**AC TEST CONDITIONS**

- Output Load : 100pF + 1TTL
- Input Levels : 0.6V, 2.4V
- Timing Measurement Reference Levels  
 Input : 0.8V, 2.2V  
 Output: 0.8V, 2.0V
- Input Rise and Fall Time : 5ns

**TIMING WAVEFORMS**



**OPERATION MODE**

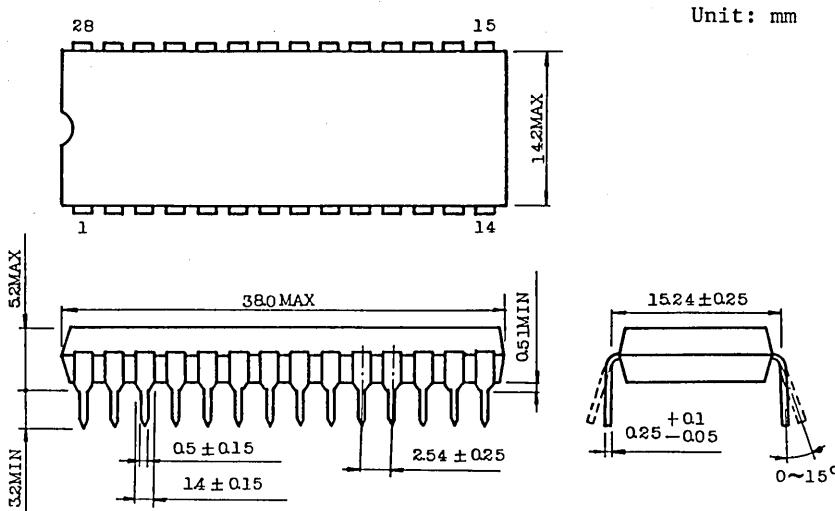
MODE	CE(CE)	A0 ~ 16	Outputs	Power
Read	L(H)	Valid	Data Out	Operating
Output Deselect	H(L)	*	High-Z	Standby

H: V<sub>IH</sub>, L: V<sub>IL</sub>, \*: V<sub>IH</sub> or V<sub>IL</sub>

**TC531000AP**  
**TC531000AF**

OUTLINE DRAWINGS

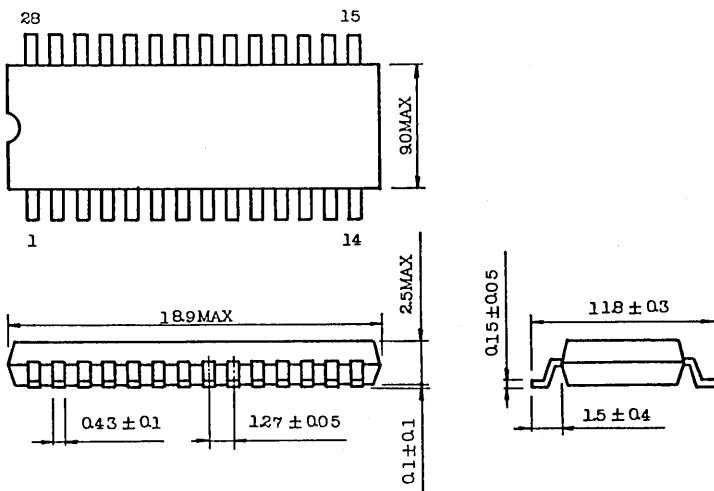
Plastic DIP



Note: Each lead pitch is 2.54mm.

All leads are located within 0.25mm of their true longitudinal position with respect to No.1 and No.28 leads.

Plastic FP



Note: Each lead pitch is 1.27mm.

All leads are located within 0.25mm of their true longitudinal position with respect to No.1 and No.28 leads.